

GIF Continuum and Continuum S

Advanced Systems for EELS & EFTEM

The Continuum series represents the next generation of electron energy loss spectroscopy (EELS) and energy-filtered transmission electron microscopy (EFTEM) systems from Gatan. By focusing on simplifying the operation of energy-loss systems without sacrificing any of the power or flexibility, the Continuum series enables new levels of productivity and data throughput. Built around new and exclusive detector systems, the Continuum delivers outstanding detector speed and quality for both EELS and EFTEM applications.

>10x higher productivity

- >8000 spectra per second at >95% duty cycle
- >10x faster system tuning
- Streamlined, workflow-based user interface

Revolutionary data quality

- Low-noise, high dynamic range CMOS detector
- Improved MTF and DQE from new XCRT™ sensor stack technology
- Full gain correction in all acquisition modes
- Exclusive dynamic focus control
- Choose the K3® electron counting direct detector for the ultimate EELS and EFTEM data quality

Emerging applications

- Energy-filtered 4D STEM*
- *In-situ* EELS and EFTEM*
- Momentum-resolved EELS*

Applications

- Materials research
- Failure analysis
- Composition and chemical analysis
- High-speed *in-situ* materials research
- Catalysis and environmental microscopy

* Requires optional components

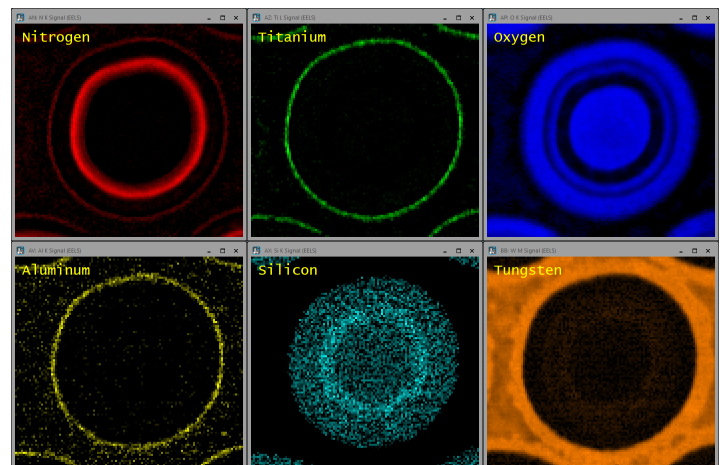
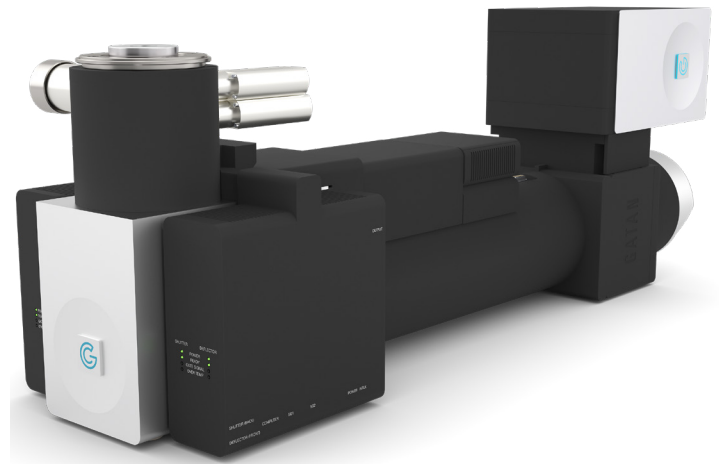


Figure 1. High-speed EELS composition map of 3D NAND device structure. 114 x 106 pixels recorded at 0.15 ms/pixel (x10 frames) greatly reducing dose rate at sample. Full, live model based quantification at each pixel allows accurate separation of overlapping edges (N-K / Ti-L / O-K and Si-K / W-M).

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Specifications

	GIF				Spectrometer
Model	Continuum ER	Continuum HR	Continuum K3	Continuum K3 HR	Continuum S
Model number	1065	1066	1069	1069HR	1077
Operating range (kV)	40 ¹ – 200/300	40 ¹ – 200/300	80 – 200/300 ²	80 – 200/300 ²	40 ¹ – 200/300
EFTEM mode	●	●	●	●	–
EELS mode	●	●	●	●	●
Detector					
Sensor type	CMOS				
Sensor size (pixel x pixel)	2048 x 2048		3456 x 3456		2048 x 64
Pixel size (µm)	18		5		18
Detector technology	High-speed XCR™		Direct detection		High-speed XCR
Performance					
Target system resolution (eV) ³	<0.3	<0.02	<0.3	<0.02	<0.3
Design energy resolution (eV) ⁴	0.1	<0.02	0.1	<0.02	0.1
Energy range (eV) ⁵	3000		3000		3000
Imaging @ full resolution (fps)	90		75		–
Spectral rate, max. (sps)	8000		3000		8000
Features	Continuum ER	Continuum HR	Continuum K3	Continuum K3 HR	Continuum S
100 ns electrostatic shutter	●	●	●	●	●
2 kV DualEELS™	●	●	●	●	●
Live STEM EELS mapping*	●	●	●	●	●
Real-time ZLP stabilization	●	●	●	●	●
Dynamic focus control	–	●	–	●	–
Integrated BF/DF detector	●	●	●	●	–
Centered beam stop	●	●	●	●	–
Continuous EFTEM	●	●	●	●	–
Recommended options					
High-speed spectrum imaging	●	●	●	●	●
ω-q slit	●	●	●	●	–
Energy-filtered 4D STEM	●	●	●	●	–
<i>In-situ</i> acquisition and analysis	●	●	●	●	–
High-speed EDS acquisition	●	●	●	●	●

Specifications are subject to change without notice.

* Requires optional components

¹30 kV option available. 30 kV option uses low-kV XCR scintillator which does not support 8 kHz spectral rate. Contact Gatan for scintillator options.

²K3 camera for 80 – 200/300 kV operation only. Add 30 – 80 kV operation with optional low-kV XCR scintillator camera. Contact Gatan for scintillator options.

³Final system resolution is dependent on (S)TEM performance and environment.

⁴Theoretical resolution in the absence of source, environment, and other instabilities.

⁵Field of view at maximum operating voltage.

